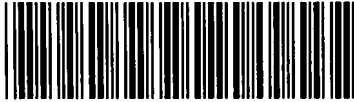


**Search Notes**

Application/Control No.

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Examiner

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Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2165

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted Primary Examiner Sam Rimell regarding 132 affidavits	4/11/2007	MAXR
Searched EAST	11/16/2007	MAXR
Double patenting search	11/16/2007	MAXR
Searched Google, Google Scholar, ACM, IEEE	11/16/2007	MAXR
See print out of search history	11/16/2007	MAXR